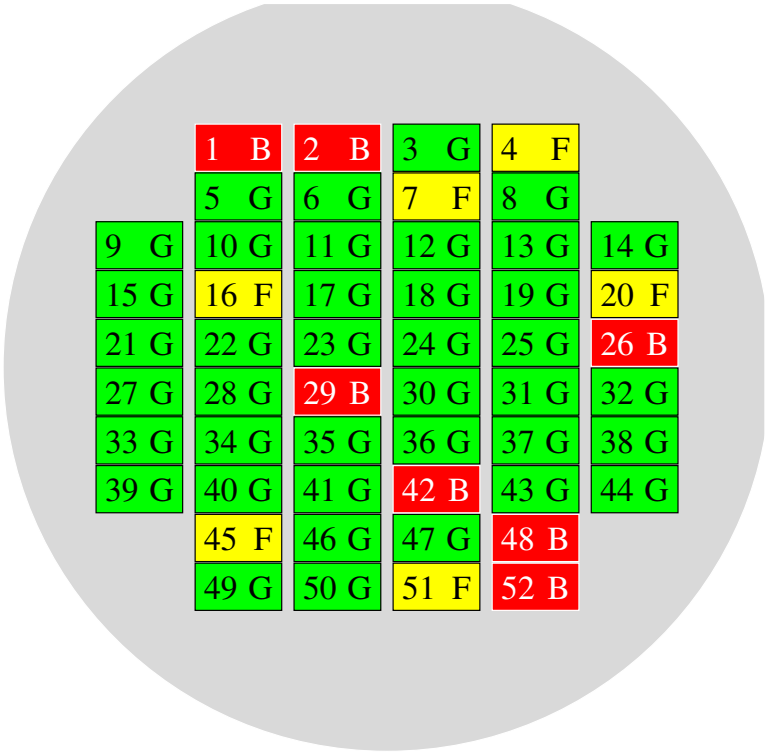
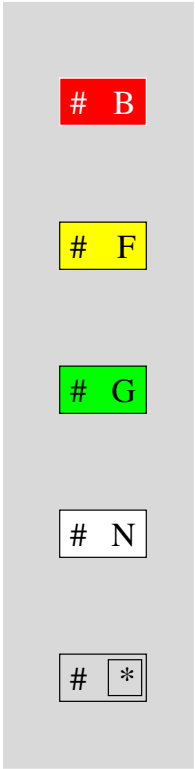
Die quality map for wafer 114 s/n: 21316-07-11

Date: 02/26/99